



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Shi-Chang Wooh  
Serial No: 09/898,815  
Filed: July 5, 2001  
For: DEFECT DETECTION SYSTEM  
AND METHOD

Group: 2878  
Examiner: Yam, Stephen K.  
Docket No: MIT-114J

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first class mail in an envelope addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on December 9, 2003.

Olga Kadish  
Olga Kadish

RESPONSE

This Response is in reply to the Office Action mailed October 15, 2003 in the subject application. In response to the Office Action, please consider the applicant's remarks as follows.

**Remarks/Arguments** begin on page 2 of this paper.